## Notice of References Cited Application/Control No. 10/509,200 Applicant(s)/Patent Under Reexamination SEIDLER ET AL. Examiner Gary F. Paumen Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0164124	08-2004	LUNDSTROM et al.	228/135
*	В	US-5,673,846	10-1997	Gruber, Peter Alfred	228/180.22
*	O	US-5,509,203	04-1996	Yamashita, Chikara	29/879
*	D	US-4,712,721	12-1987	Noel et al.	228/56.3
*	Ε	US-3,744,129	07-1973	Dewey, Jr., Daniel	29/837
*	F	US-2002/0029905	03-2002	Okada et al.	174/263
*	G	US-7,043,830	05-2006	Farnworth, Warren M.	29/842
*	Ι	US-6,534,726	03-2003	Okada et al.	174/263
*	_	US-6,452,112	09-2002	Terashima et al.	174/260
*	7	US-6,294,745	09-2001	Gruber, Peter Alfred	174/263
*	K	US-5,471,368	11-1995	Downie et al.	361/760
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.